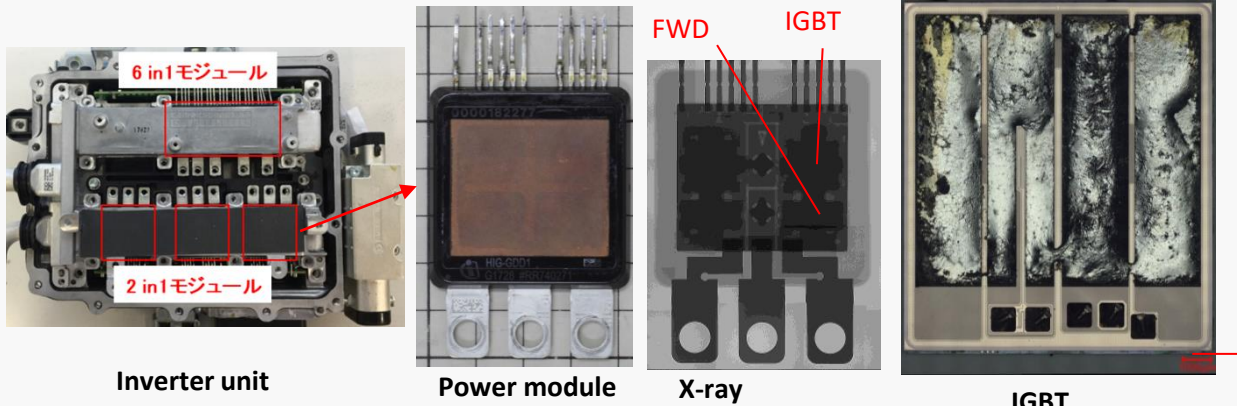


INFINEON 2 in 1* POWER MODULE STRUCTURE ANALYSIS REPORT – Product used in the Hyundai IONIQ PHEV



Inverter unit

Power module

X-ray

IGBT

* One IGBT and one free-wheeling diode form one pair. There are two pairs in one package. This is referred to as 2 in 1. There are two types of power modules in this inverter unit: one is 2 in 1, the other is 6 in 1. We analyzed the 2 in 1 inverter.

Product outline

The Electric Power Control Unit (EPCU) found within the 2018 Hyundai IONIQ PHEV uses Infineon's third generation half-bridge IGBT power module. This product is estimated to be equivalent to Infineon's "FF400R07A01E3_S6" 700V/400A component, a part of the HybridPACK™ family.

Basic features

- Double-sided cooling structure with DBC boards are attached to both sides of the package.
- A spacer is used to connect the IGBT die to the DBC board within the package.
- There are current sense, emitter sense, and temperature sense pads on the IGBT chip.
- The IGBT process is estimated to be equivalent to TRENCHSTOP™ IGBT3.

Report contents

- Estimation of the internal layout from the results of module plane analysis.
- Cross section and material analysis with focus on components of the double-sided cooling structure.
- IGBT die analysis: plane and cross-section analysis of the cell area and the die edge.
- The area and area ratio of the current sensing emitter are calculated from plane observations.
- Structure analysis of the temperature sense diode.
- Thermal resistance estimation based on structural analysis results.

Note: The report price may change over time. For current price contact info@ltecusa.com.

19G-0040-1

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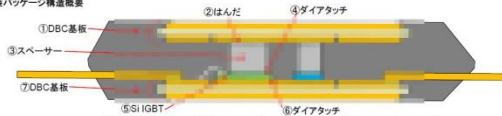
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Excerpts from the analysis report

表 4: 異種パッケージ構造概要



番号	測定箇所	測長	材料
1	基板(DBC)		
1-1	上銅箔層		
1-2	絶縁層		
1-3	添加物		
1-4	下銅箔層		
2	はんだ		
3	スペースャ		
4	ダイアタッチ		
5	IGBT		
5-1	表面保護膜		
5-2	パッシベーション		
5-3	基板		
5-4	表面電極-1		
5-5	表面電極-2		
5-6	表面電極-3		
5-7	表面電極-4		
6	ダイアタッチ		
7	基板(DBC)		
7-1	上銅箔層		
7-2	絶縁層		
7-3	添加物		
7-4	下銅箔層		

2-2. パッケージ平面構造解析

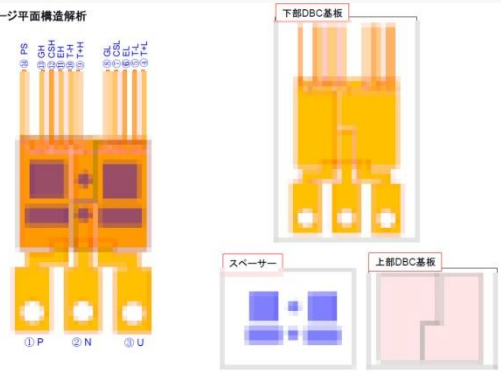
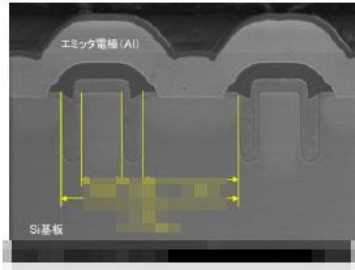


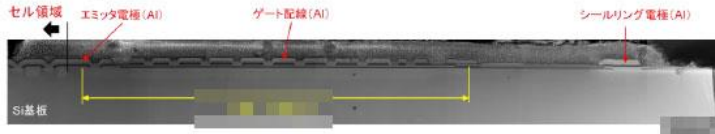
Fig. 2-2-5 パッケージレイアウト模式図

断面構造解析

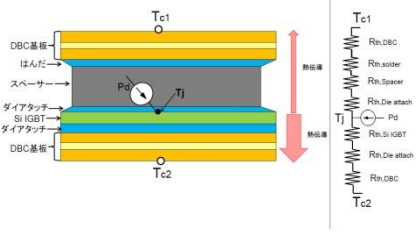
セル部



外周部



4-1. IGBT熱解析: 熱抵抗モデル



4-2. IGBT熱解析: 1-D Rth、Jc推定

位置	材料	厚さ [mm]	熱伝導率 [W/mK]	熱抵抗 [K/W]
上側 DBC 基板	銅箔層	0.01	400	0.00025
	絶縁層	0.05	0.2	0.0025
	添加物	0.01	0.2	0.0005
	銅箔層	0.01	400	0.00025
はんだ	はんだ	0.05	10	0.005
	はんだ	0.05	10	0.005
スペースャ	スペースャ	0.1	0.2	0.005
	スペースャ	0.1	0.2	0.005
ダイアタッチ	銅箔層	0.01	400	0.00025
	絶縁層	0.05	0.2	0.0025
	添加物	0.01	0.2	0.0005
	銅箔層	0.01	400	0.00025
Si IGBT	Si IGBT	0.1	150	0.0067
	Si IGBT	0.1	150	0.0067
下側 DBC 基板	銅箔層	0.01	400	0.00025
	絶縁層	0.05	0.2	0.0025
	添加物	0.01	0.2	0.0005
	銅箔層	0.01	400	0.00025

・IGBT (スイッチあたり1つのトランジスタ)
 $R_{th,jc} = \dots \text{ } ^\circ\text{C/W per switch}$

・熱抵抗の成分は左表 (①~⑬)。
 ・IGBTチップの上側 (①~⑦) で支配的となっているのは、
 ・IGBTチップの下側のみの熱抵抗が